

# ICI E450 L-EFT

Pulse E-Field Source



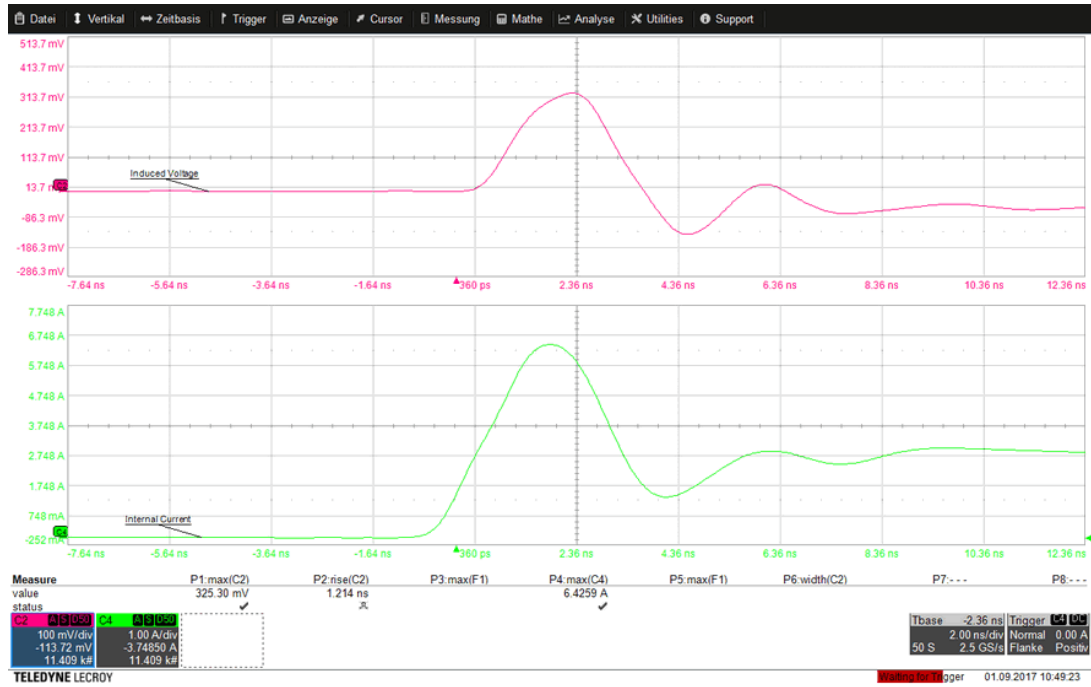
## Short description

The ICI E450 L-EFT pulse electric field source couples fast transient pulses into a test IC (open die). This allows for fault injection attacks or testing the immunity of individual areas of the IC.

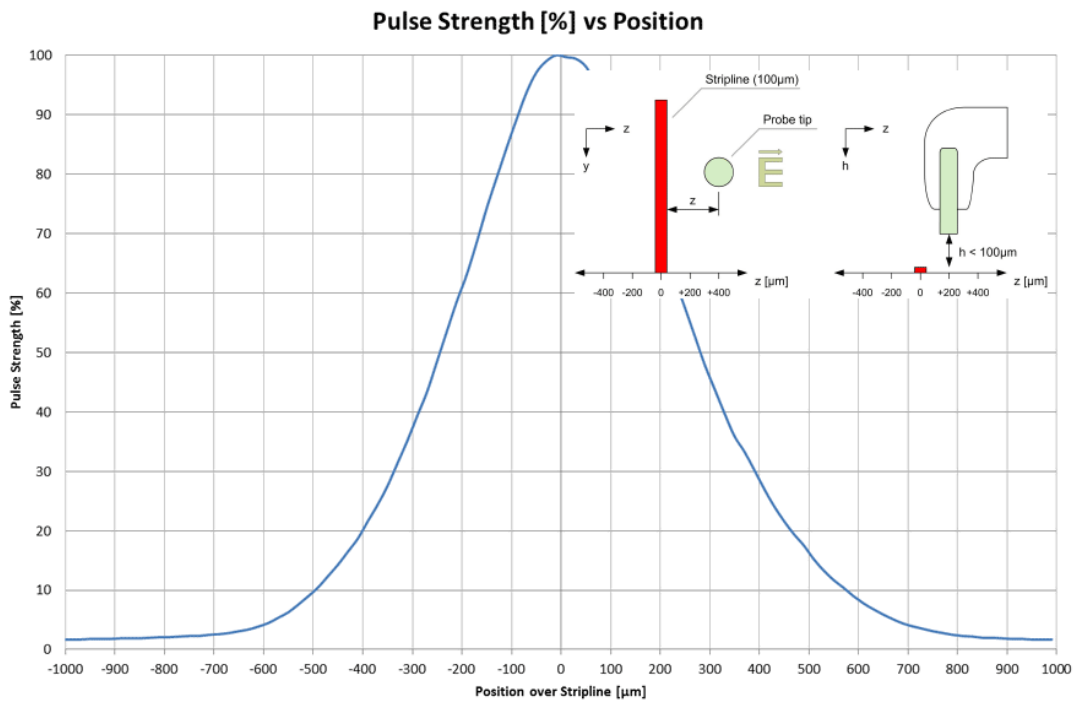
## Technical parameters

<b>Probe head dimensions</b>	Ø 450 µm
<b>Max. Displacement Current (Stripline 100 µm)</b>	7 mA
<b>Pulse parameter</b>	
Rise time	< 2 ns
Repetition frequency	0.1 Hz - 20 kHz
Polarity (set by software)	+ / - / alternating
<b>Measuring output</b>	50 Ω
<b>Trigger-pulse delay (Bypass Mode - Delay Line)</b>	
min. Trigger-pulse delay (typ.)	70 ns
max. Trigger-pulse delay (typ.)	420 ns
max. Jitter (typ.)	± 1 ns
<b>Supply voltage</b>	BPS 202
<b>Weight</b>	70 g
<b>Sizes (L x W x H)</b>	(26 x 43 x 53) mm

Pulse shape



Transverse scan



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Application of ICI E450 L-EFT pulse E-field source

